

MAR 20 2006

Sheet 1 of 1

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07844-458001	Application No. 09/657,949
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant John Peterson	
		Filing Date September 8, 2000	Group Art Unit 3625 2624

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
K3P	AA	7,006,707	02/28/06	Peterson	348	36	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
	AL						Yes	No
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature <i>K3P</i>	Date Considered 3/29/06
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Disclosure Form (PTO-1449)

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Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR 51.98(b))		Applicant John Peterson	
		Filing Date September 8, 2000	Group Art Unit 2625- 2624

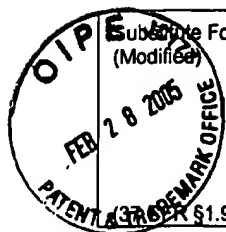
U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
K2P	AA	6,424,351	07/2002	Bishop, et al.	345	582	
	AB	6,567,085	05/2003	Edmark	345	427	
	AC	6,674,484	01/2004	Boland, et al.	348	580	
✓	AD	6,778,207	08/2004	Lee, et al.	348	36	
	AE						
	AF						
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	AH						
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	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No
	AL						
	AM						
	AN						
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
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	AT	

Examiner Signature K2P/ate	Date Considered 4/17/06
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Substitute Disclosure Form (PTO-1449)



Substitute Form PTO-1449

(Modified)

U.S. Department of Commerce
Patent and Trademark Office

Attorney's Docket No.

07844-458001

Application No.

09/657,949

**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

Applicant

John Peterson

Filing Date

September 8, 2000

Group Art Unit

2625

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
WZP	AA	5,987,164	11/16/99	Szeliski, et al.	382	854	
	AB	6,084,592	7/00	Shum, et al.	345	420	
	AC	6,389,179	5/02	Katayama	382	284	
	AD	6,532,036	3/03	Peleg, et al.	348	36	
	AE	6,643,413	11/03	Shum, et al.	382	284	
	AF	6,704,041	3/04	Katayama	348	36	
✓	AG	6,714,689	3/04	Yano, et al.	382	284	
	AH						
	AI						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
WZP	AJ	WO 98/02844	1/22/98	Peleg, et al.	—	—	X	
	AK							
	AL							
	AM							
	AN							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
WZP	AO	Paul S. Heckbert, "Fundamentals of Texture Mapping and Image Warping", <i>Master's Thesis</i> under the direction of Carlo Séquin, Dept. of Electrical Engineering and Computer Science, University of California, Berkeley, California, June 17, 1989, 86 pages
	AP	Shum et al., "Rendering with Concentric Mosaics," (1999) Microsoft Research, pages 299-306
	AQ	Xiong, et al. "Registration, Calibration and Blending in Creating High Quality Panoramas", Applications of Computer Vision, Proceedings of the Fourth IEEE Workshop, Los Alamitos, CA October 19-21, 1998, pp. 69-74
✓	AR	

Examiner Signature

WZPattell

Date Considered

4/12/06

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U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>QZL</i>	AA	5,185,808	02/1993	Cok	382	284	
	AB	5,920,657	07/1999	Bender, et al.	382	284	
	AC	6,005,545	12/21/99	Nishida, et al.	382	603	
	AD	6,411,742	06/25/02	Peterson	382	284	
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
<i>QZL</i>	AK	WO 01/88838	11/22/01	WIPO	—	—	X	
	AL							
	AM							
	AN							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
<i>QZL</i>	AO	Burt, et al. "A Multiresolution Spline With Application to Image Mosaics", ACM Transactions on Graphics, Vol. 2, No. 4, October 1983, pp. 217-236
	AP	Porter, et al. "Compositing Digital Images", Computer Graphics, Vol. 18, No. 3, July 1984, pp. 253-259
	AQ	Lance Williams, "Pyramidal Parametrics", Computer Graphics, Vol. 17, No. 3, July 1983, pp. 1-11
	AR	

Examiner Signature <i>QZL at el</i>	Date Considered <i>4/17/06</i>
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